# Hex D Flip-Flop with Common Clock and Reset

This device consists of six D flip-flops with common Clock and Reset inputs. Each flip-flop is loaded with a low-to-high transition of the Clock input. Reset is asynchronous and active low. All inputs/outputs are standard CMOS compatible.

#### **Features**

• Output Drive Compatibility: 10 LSTTL Loads

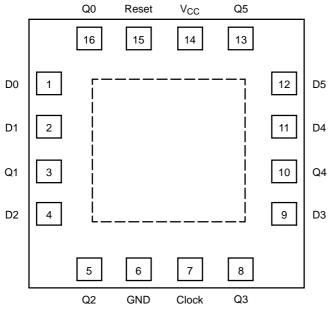
• Outputs Directly Interface to CMOS

• Operating Voltage Range: 2.0 to 6.0 V

• Low Input Current: 1.0 μA

• MSL Level 1

Chip Complexity: 162 FETPb–Free Package is Available\*



Center pad on bottom may be connected to  $V_{CC}$  of device. This pad must be isolated or connected to  $V_{CC}$ .

Figure 1. PIN ASSIGNMENT (Top View)



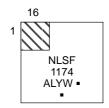
## ON Semiconductor®

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QFN-16 MN SUFFIX CASE 485G

#### **MARKING DIAGRAM**



NLSF1174 = Device Code

A = Assembly Location

L = Wafer Lot
Y = Year
W = Work Week
■ Pb-Free Package

(Note: Microdot may be in either location)

#### **FUNCTION TABLE**

	Inputs		
Reset	Clock	D	Q
L	Х	Х	L
Н		Н	Н
Н		L	L
Н	L	Х	No Change
Н		Х	No Change

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NLSF1174MNR2	QFN-16	3000 / Tape & Reel
NLSF1174MNR2G	QFN-16 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

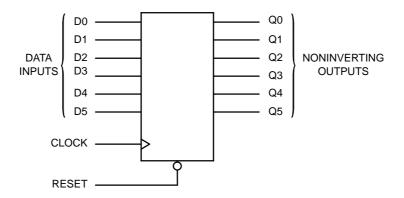


Figure 2. LOGIC DIAGRAM

## **DESIGN/VALUE TABLE**

Design Criteria	Value	Unit
Internal Gate Count*	40.5	ea
Internal Gate Propagation Delay	1.5	ns
Internal Gate Power Dissipation	5.0	μW
Speed Power Product	.0075	рJ

<sup>\*</sup>Equivalent to a two-input NAND gate.

## **MAXIMUM RATINGS**

	Parameter	Symbol	Value	Unit
DC Supply Voltage	(Referenced to GND)	V <sub>CC</sub>	-0.5 to +7.0	V
DC Input Voltage	(Referenced to GND)	V <sub>IN</sub>	-1.5 to V <sub>CC</sub> +1.5	V
DC Output Voltage	(Referenced to GND) (Note 1)	V <sub>OUT</sub>	$-0.5$ to $V_{CC} + 0.5$	V
DC Input Current, per Pin		I <sub>IN</sub>	±20	mA
DC Output Current, per Pin		I <sub>OUT</sub>	±25	mA
DC Supply Current, V <sub>CC</sub> and GND	Pins	I <sub>CC</sub>	±50	mA
Storage Temperature Range		T <sub>STG</sub>	-65 to +150	°C
Lead Temperature, 1 mm from Cas	e for 10 Seconds PDIP, SOIC, TSSOP	T <sub>L</sub>	260	°C
Junction Temperature Under Bias		T <sub>J</sub>	+ 150	°C
Thermal Resistance	QFN	$\theta_{\sf JA}$	80	°C/W
Power Dissipation in Still Air at 85°0	QFN QFN	P <sub>D</sub>	800	mW
Moisture Sensitivity		MSL	Level 1	
Flammability Rating	Oxygen Index: 30 to 35	F <sub>R</sub>	UL 94 V-0 @ 0.125 in	
ESD Withstand Voltage	Human Body Model (Note 2) Machine Model (Note 3) Charged Device Model (Note 4)	V <sub>ESD</sub>	> 2000 > 100 > 500	V
Latchup Performance	Above V <sub>CC</sub> and Below GND at 85°C (Note 5)	I <sub>LATCHUP</sub>	±300	mA

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- I<sub>O</sub> absolute maximum rating must be observed.
- 2. Tested to EIA/JESD22-A114-A.
- 3. Tested to EIA/JESD22-A115-A.
- 4. Tested to JESD22-C101-A.
- 5. Tested to EIA/JESD78.
- 6. For high frequency or heavy load considerations, see the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

#### RECOMMENDED OPERATING CONDITIONS

Parameter	Symbol	Min	Max	Unit	
DC Supply Voltage	(Referenced to GND)	V <sub>CC</sub>	2.0	6.0	V
DC Input Voltage, Output Voltage	(Referenced to GND) (Note 7)	V <sub>IN</sub> , V <sub>OUT</sub>	0	V <sub>CC</sub>	V
Operating Temperature, All Package Types		T <sub>A</sub>	- 55	+125	°C
Input Rise and Fall Time (Figure 4)	$V_{CC} = 2.0 \text{ V}$ $V_{CC} = 4.5 \text{ V}$ $V_{CC} = 6.0 \text{ V}$	t <sub>r</sub> , t <sub>f</sub>	0 0 0	1000 500 400	ns

<sup>7.</sup> Unused inputs may not be left open. All inputs must be tied to a high- or low-logic input voltage level.

## DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

			v <sub>cc</sub>	Guaranteed Limit		t	
Parameter	Test Conditions	Symbol	٧	-55°C to 25°C	≤ <b>85°C</b>	≤125°C	Unit
Minimum High-Level Input Voltage	$V_{OUT} = 0.1 \text{ V or } V_{CC} - 0.1 \text{ V}$ $ I_{OUT}  \le 20  \mu\text{A}$	V <sub>IH</sub>	2.0 4.5 6.0	1.5 3.15 4.2	1.5 3.15 4.2	1.5 3.15 4.2	V
Maximum Low-Level Input Voltage	$V_{OUT}$ = 0.1 V or $V_{CC}$ – 0.1 V $ I_{OUT}  \le 20 \mu A$	V <sub>IL</sub>	2.0 4.5 6.0	0.5 1.35 1.8	0.5 1.35 1.8	0.5 1.35 1.8	٧
Minimum High-Level Output Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $ I_{OUT}  \le 20  \mu\text{A}$	V <sub>OH</sub>	2.0 4.5 6.0	1.9 4.4 5.9	1.9 4.4 5.9	1.9 4.4 5.9	V
	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $ I_{OUT}  \le 4.0 \text{ mA}$ $ I_{OUT}  \le 5.2 \text{ mA}$		4.5 6.0	3.98 5.48	3.84 5.34	3.7 5.2	
Maximum Low-Level Output Voltage	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $ I_{OUT}  \le 20  \mu\text{A}$	V <sub>OL</sub>	2.0 4.5 6.0	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V
	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $ I_{OUT}  \le 4.0 \text{ mA}$ $ I_{OUT}  \le 5.2 \text{ mA}$		4.5 6.0	0.26 0.26	0.33 0.33	0.4 0.4	
Maximum Input Leakage Current	V <sub>IN</sub> = V <sub>CC</sub> or GND	I <sub>IN</sub>	6.0	± 0.1	±1.0	±1.0	μΑ
Maximum Quiescent Supply Current (per Package)	$V_{IN} = V_{CC}$ or GND $I_{OUT} = 0 \mu A$	Icc	6.0	4.0	40	160	μА

<sup>8.</sup> Information on typical parametric values, along with high frequency or heavy load considerations, can be found in the ON Semiconductor High–Speed CMOS Data Book (DL129/D).

## AC ELECTRICAL CHARACTERISTICS ( $C_L = 50 \text{ pF}$ , Input $t_r = t_f = 6.0 \text{ ns}$ )

		v <sub>cc</sub>	Guaranteed Limit			
Parameter	Symbol	V	-55°C to 25°C	≤ <b>85°C</b>	≤125°C	Unit
Maximum Clock Frequency (50% Duty Cycle) (Figures 4 and 7)	f <sub>max</sub>	2.0 4.5 6.0	6.0 30 35	4.8 24 28	4.0 20 24	MHz
Maximum Propagation Delay, Clock to Q (Figures 5 and 7)	t <sub>PLH</sub> t <sub>PHL</sub>	2.0 4.5 6.0	110 22 19	140 28 24	165 33 28	ns
Maximum Propagation Delay, Reset to Q (Figures 2 and 7)	t <sub>PLH</sub> t <sub>PHL</sub>	2.0 4.5 6.0	110 21 19	140 28 24	160 32 27	ns
Maximum Output Transition Time, Any Output (Figures 4 and 7)	t <sub>TLH</sub> t <sub>THL</sub>	2.0 4.5 6.0	75 15 13	95 19 16	110 22 19	ns
Maximum Input Capacitance	C <sub>in</sub>		10	10	10	pF
		Typical @ 25°C, V <sub>CC</sub> = 5.0 V				
Power Dissipation Capacitance, per Enabled Output (Note 10)	C <sub>PD</sub>		62	2		pF

<sup>9.</sup> For propagation delays with loads other than 50 pF, and information on typical parametric values, see the ON Semiconductor High-Speed

CMOS Data Book (DL129/D).

10. Used to determine the no-load dynamic power consumption: P<sub>D</sub> = C<sub>PD</sub> V<sub>CC</sub><sup>2</sup>f + I<sub>CC</sub> V<sub>CC</sub>. For load considerations, see the ON Semiconductor High-Speed CMOS Data Book (DL129/D).

# **TIMING REQUIREMENTS** ( $C_L = 50 \text{ pF}$ , Input $t_r = t_f = 6.0 \text{ ns}$ )

				Guaranteed Limit						
			v <sub>cc</sub>	−55°C	to 25°C	≤8	35°C	≤12	25°C	
Parameter	Figure	Symbol	V	Min	Max	Min	Max	Min	Max	Unit
Minimum Setup Time, Data to Clock	6	t <sub>su</sub>	2.0 4.5 6.0	50 10 9.0		65 13 11		75 15 13		ns
Minimum Hold Time, Clock to Data	6	t <sub>h</sub>	2.0 4.5 6.0	5.0 5.0 5.0		5.0 5.0 5.0		5.0 5.0 5.0		ns
Minimum Recovery Time, Reset Inactive to Clock	5	t <sub>rec</sub>	2.0 4.5 6.0	5.0 5.0 5.0		5.0 5.0 5.0		5.0 5.0 5.0		ns
Minimum Pulse Width, Clock	4	t <sub>w</sub>	2.0 4.5 6.0	75 15 13		95 19 16		110 22 19		ns
Minimum Pulse Width, Reset	5	t <sub>w</sub>	2.0 4.5 6.0	75 15 13		95 19 16		110 22 19		ns
Maximum Input Rise and Fall Times	4	t <sub>r</sub> , t <sub>f</sub>	2.0 4.5 6.0		1000 500 400		1000 500 400		1000 500 400	ns

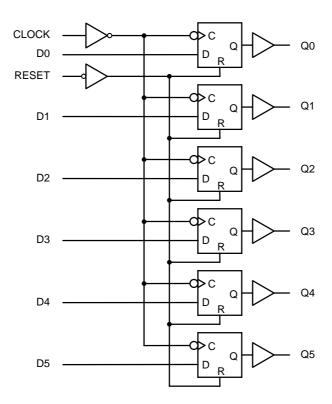


Figure 3. Expanded Logic Diagram

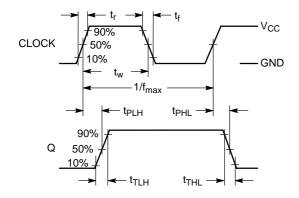


Figure 4. Switching Waveform

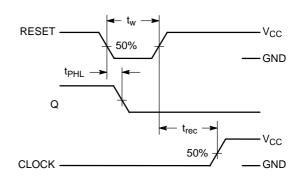


Figure 5. Switching Waveform

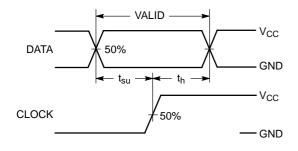
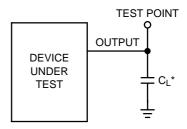


Figure 6. Switching Waveform



\*Includes all probe and jig capacitance

Figure 7. Test Circuit

## PIN1/PRODUCT ORIENTATION CARRIER TAPE

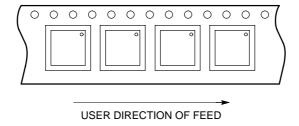


Figure 8.

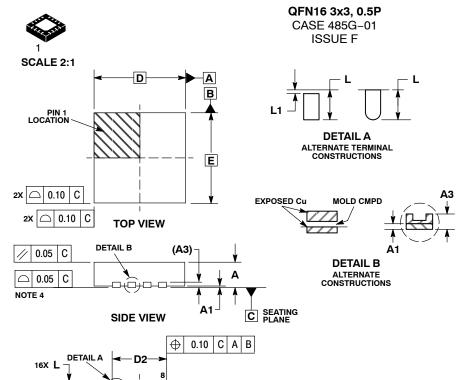
16X K

16

**BOTTOM VIEW** 

е

e/2



**E2** 

0.10 Ф

0.05 С NOTE 3

CAB

16X b

**DATE 22 JUN 2011** 

#### NOTES:

- ANTES.

  1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

  2. CONTROLLING DIMENSION: MILLIMETERS.
- 3.
- CONTROLLING DIMENSION: MILLIMETERS. DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN 0.25 AND 0.30 MM FROM TERMINAL COPLANARITY APPLIES TO THE EXPOSED PAD AS WELL AS THE TERMINALS.

	MILLIMETERS						
DIM	MIN	MIN NOM					
Α	0.80	0.90	1.00				
<b>A</b> 1	0.00	0.03	0.05				
А3	0	.20 REF					
b	0.18	0.24	0.30				
D	3	.00 BSC					
D2	1.65	1.75	1.85				
Е	3	.00 BSC	)				
E2	1.65	1.75	1.85				
е	0.50 BSC						
K	0.18 TYP						
L	0.30	0.40	0.50				
L1	0.00	0.08	0.15				

### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code

= Assembly Location

L = Wafer Lot = Year

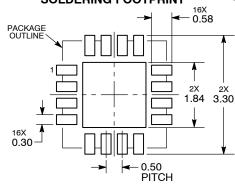
W = Work Week

= Pb-Free Package (Note: Microdot may be in either location)

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■",

may or may not be present.

#### RECOMMENDED **SOLDERING FOOTPRINT\***



DIMENSIONS: MILLIMETERS

\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	QFN16, 3X3 MM, 0.5 PITCH	I	PAGE 1 OF 1		

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